

Notice of References Cited

Application/Control No.

10/530,047

Applicant(s)/Patent Under
Reexamination
YABE ET AL.

Examiner

STEPHEN KO

Art Unit

1792

Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-5,014,727 | 05-1991 | Aigo, Seiichiro | 134/102.2 |
| * | B | US-2002/0027070 | 03-2002 | Oyokota et al. | 204/257 |
| * | C | US-4,832,941 | 05-1989 | Berwing et al. | 424/9.52 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| * | N | 55-180425 | 12-1980 | Japan | | |
| | O | 2001-328069 | 11-2001 | Japan | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.